**☑** 004/016

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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re:

Detlef Michelsson

Confirmation

5672

No:

Serial No:

10/772,510

Group:

2609

Filed:

February 5, 2004

Examiner:

Fujita, Katrina R

For:

Method and Apparatus for

**Examining Semiconductor Wafers** 

in a Context of DIE/SAW Design

Customer No.: 29127

Attorney

21295.74US (H5742US)

Docket No.

## AMENDMENT AND REPLY

VIA FACSIMILE: 571-273-8300 Commissioner for Patents

P.O. Box 1450

Alexandria, Virginia 22313-1450

Sir:

In response to the pending Office Action, mailed February 5, 2007, please amend the above-captioned application as follows:

-amendments to the specification are set forth in section a);

-amendments to the claims are reflected in the listing of claims in section b);

and finally, reconsideration is requested in view of the remarks set forth in section c). .